



Report No.: SR081131-1

Ref No.: CP2008-1301SH

Date: 12/11/2008

Page: 1 of 7

Test Report

Applicant: Shanghai Rectron Electronic Co., Ltd.
Address: 188#, New Street, Xia-Sha Town, Nan-Hui Xian, Shanghai, China

Sample Description: The submitted sample(s) stated to be Molding Compound

Model No.: KL-1000-HF Listed No.: --

Lot No.: -- Main Substances: Epoxy

Buyer: SONY

Supplier/Manufacture: Shanghai Rectron Electronic Co., Ltd.

Make use of the following package products:

SMA(L)/SMB(L)/SMC(L)/SMX/SOD123/SOD123F(L)/MELF/MINI

MELF/R1/A405/DO41/DO15/R3/R6/1.5KE/DO201/DO204/HVM/HVP/DBS/DB/DBLS/SLDBS/MDS/BD
B/RS1/RS2/RS4/RS6/RS8//0RB15/WOM/RC2/BR3/BR6//BR8/BR10/BR15(W)-25(W)-35(W)/MB15(W)-2
5(W)-35(W)/MP15(W)-25(W)-35(W)/RS1M-2M-4M-6M-10M-15M-20M-25M-35M/RBU4M-6M-8M-10M
/(I)TO220A/ITO220/DPK/D2PAK/TO247/SOT23/MDS

Date Received: Nov.25, 2008
Test Period: Nov.25, 2008 – Dec.11, 2008
Test Location: Machinery & Electrical Products Testing Center of Shanghai Entry-Exit
Inspection and Quarantine Bureau of P.R. China
No. 1208, Minsheng Road Pudong Shanghai 200135, P.R.China
Test Requested: Please refer to next pages
Test Method: Please refer to next pages
Test Result: Please refer to next pages

For and on behalf of
SMEC
INSPECTORATE (SHANGHAI) LTD.

Miao Junwen
Director

George Cao
Sr. Supervisor

Report No.: SR081131-1

Test Report

Ref No.: CP2008-1301SH

Date: 12/11/2008

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Test Requested

- 1) To determine the Cadmium and Lead content of the submitted sample(s)
- 2) To determine the Mercury content of the submitted sample(s)
- 3) To determine the Hexavalent Chromium content of the submitted sample(s)
- 4) To determine the PBBs and PBDEs contents of the submitted sample(s)
- 5) To determine the Halogen contents of the submitted sample(s)
- 6) To determine the PFOS&PFOA contents of the submitted sample(s)
- 7) To determine the TBBP-A contents of the submitted sample(s)
- 8) To determine the Phthalates DBP, BBP, DEHP, DINP, DNOP, DIDP and DNHP contents of the submitted sample(s)

Test Method

- 1) With reference to US EPA 3050B/ 3051/ 3052 and other acid digestion methods to determine the content of Cadmium and Lead by ICP-AES or AAS
- 2) With reference to US EPA 3052 to determine the content of Mercury by ICP-AES
- 3) With reference to US EPA 3060A/ 7196A to determine the content of Hexavalent Chromium by UV-Vis
- 4) With reference to US EPA 8081A/ 8270D/ 3540C/ 3550C to determine the contents of PBBs and PBDEs by GC/MS
- 5) With reference to BS EN14582:2007. Determination of Halogen by IC
- 6) With reference to US EPA 3540C/3550C method. Analysis was performed by LC-MS.
- 7) With reference to US EPA3540C/8270D. Determination of TBBP-A by GC/MS
- 8) With reference to ASTM D3421-75. Analysis was performed by GC-MS

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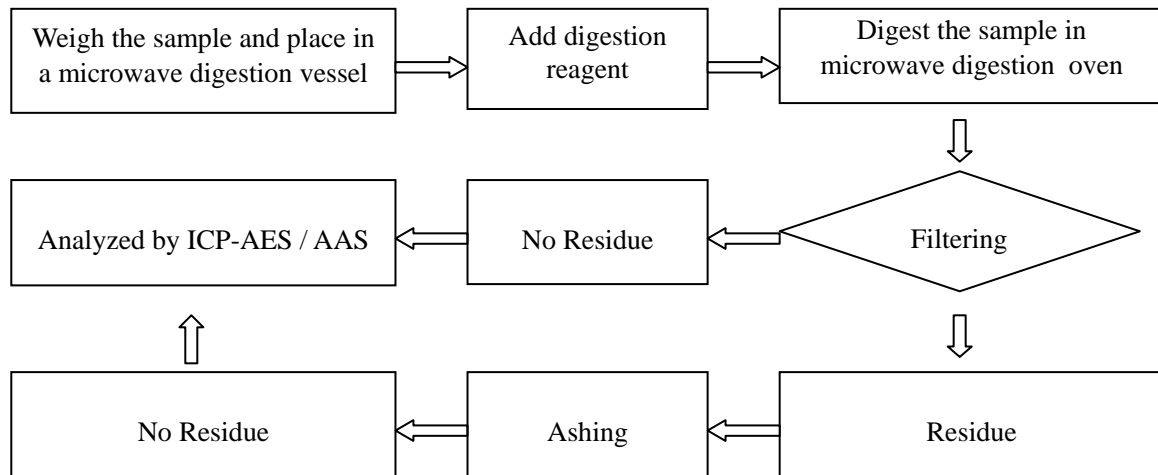
Date: 12/11/2008

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Test Report

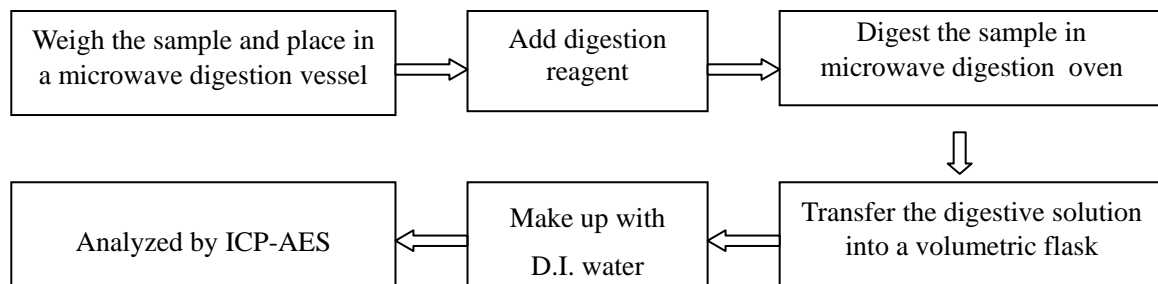
Test Process

1) Cd and Pb Measurement Flowchart



The samples were dissolved totally by pre-conditioning method according to above flow chart

2) Hg Measurement Flowchart



Report No.: SR081131-1

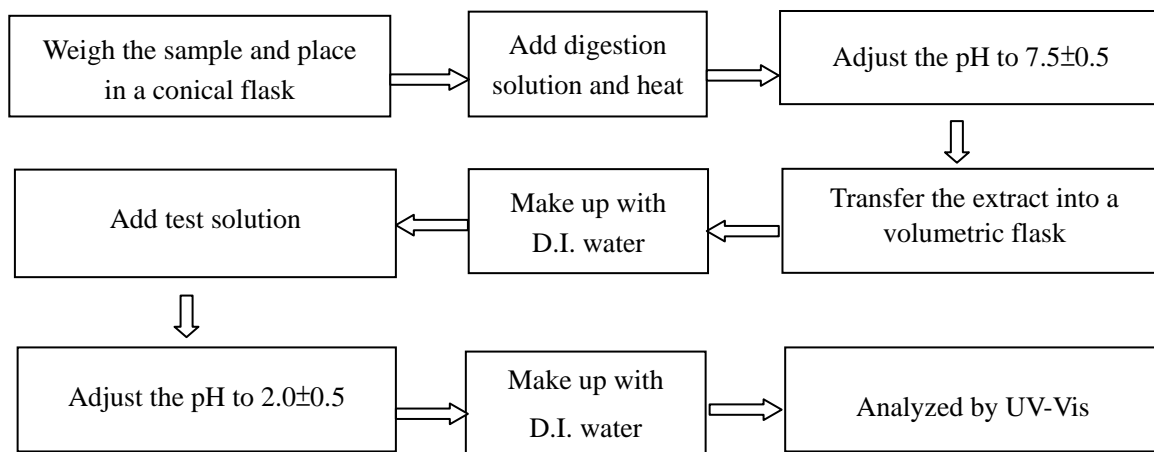
Ref No.: CP2008-1301SH

Date: 12/11/2008

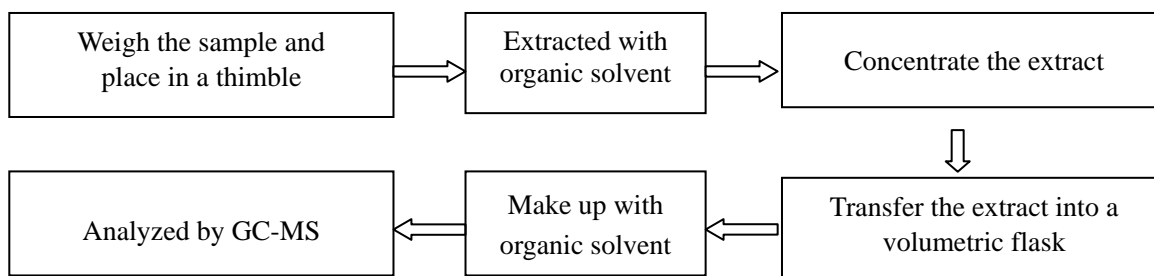
Page: 4 of 7

Test Report

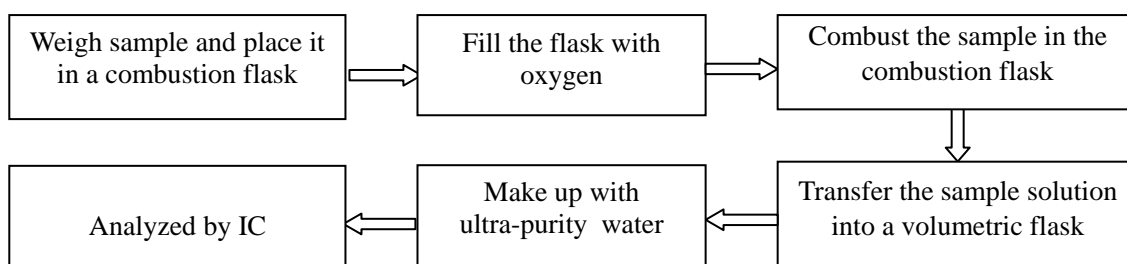
3) Cr⁶⁺ Measurement Flowchart



4) PBBs /PBDEs Measurement Flowchart



5) Halogen Measurement Flowchart



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Test Report

Test result summary on sample: Molding Compound

Test Item	Unit	Result	Reporting Limit
Cadmium(Cd)	mg/kg	ND	2
Lead (Pb)	mg/kg	ND	2
Mercury (Hg)	mg/kg	ND	2
Hexavalent Chromium (CrVI)	mg/kg	ND	2
Polybrominated Biphenyls (PBBs)			
1. Monobromobiphenyls	mg/kg	ND	5
2. Dibromobiphenyls	mg/kg	ND	5
3. Tribromobiphenyls	mg/kg	ND	5
4. Tetrabromobiphenyls	mg/kg	ND	5
5. Pentabromobiphenyls	mg/kg	ND	5
6. Hexabromobiphenyls	mg/kg	ND	5
7. Heptabromobiphenyls	mg/kg	ND	5
8. Octabromobiphenyls	mg/kg	ND	5
9. Nonabromobiphenyls	mg/kg	ND	5
10. Decabromobiphenyls	mg/kg	ND	5
Sum of PBBs	mg/kg	ND	--
Polybrominated Diphenyl Ethers (PBDEs)			
1. Monobromodiphenyl ethers	mg/kg	ND	5
2. Dibromodiphenyl ethers	mg/kg	ND	5
3. Tribromodiphenyl ethers	mg/kg	ND	5
4. Tetrabromodiphenyl ethers	mg/kg	ND	5
5. Pentabromodiphenyl ethers	mg/kg	ND	5
6. Hexabromodiphenyl ethers	mg/kg	ND	5
7. Heptabromodiphenyl ethers	mg/kg	ND	5
8. Octabromodiphenyl ethers	mg/kg	ND	5
9. Nonabromodiphenyl ethers	mg/kg	ND	5
10. Decabromodiphenyl ethers	mg/kg	ND	5
Sum of PBDE	mg/kg	ND	--

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Test Report

Test Item	Unit	Result	Reporting Limit
Fluorine(F)	mg/kg	177.3	10
Chlorine (Cl)	mg/kg	110.6	10
Bromine (Br)	mg/kg	6503.8	10
Iodine (I)	mg/kg	ND	30
PFOS			
PFOS	mg/kg	ND	10
PFOA			
PFOA	mg/kg	ND	10
TBBP-A			
TBBP-A	mg/kg	111	5
Phthalates			
Di-butyl phthalate(DBP)	%	ND	0.003
Benzyl butyl phthalate(BBP)	%	ND	0.003
Di-2-ethylhexyl phthalate(DEHP)	%	ND	0.003
Di-isononyl phthalate(DINP)	%	ND	0.01
Di-n-octyl phthalate(DNOP)	%	ND	0.003
Di-isodecyl phthalate(DIDP)	%	ND	0.01
Di-n-hexyl phthalate(DNHP)	%	ND	0.003

Note:

- 1) mg/kg = ppm
- 2) ND = Not detected, which will be showed if below reporting limit
- 3) -- = Not applicable
- 4) If residue occurs after digestion, it will be treated by dry ashing for total digestion
- 5) Reference information: EU Directive 2006/122/EC
 - i) May not be placed on the market or used as a substance or constituent of preparations in a concentration equal to or higher than 0.005 % by mass.
 - ii) May not be placed on the market in semi-finished products or articles, or parts thereof, if the concentration of PFOS is equal to or higher than 0.1 % by mass calculated with reference to the mass of structurally or microstructurally distinct parts that contain PFOS or, for textiles or other coated materials, if the amount of PFOS is equal to or higher than $1 \mu \text{g/m}^2$ of the coated material.

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Date: 12/11/2008

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Test Report

ANNEX

Sample Photo



*****End of Report*****



上海出入境检验检疫局
机电产品检测技术中心

Machinery & Electrical Products Testing Center of Shanghai CIQ



No. L0232

Report No.: SR081131-2

Ref No.: CP2008-1301SH

Date: 12/1/2008

Page: 1 of 4

Test Report

Applicant: Shanghai Rectron Electronic Co., Ltd.
Address: 188#, New Street, Xia-Sha Town, Nan-Hui Xian, Shanghai, China

Sample Description: The submitted sample(s) stated to be Solder wafer

Model No.: -- Listed No.: --

Lot No.: -- Main Substances: Pb/Sn/Ag

Buyer: SONY

Supplier/Manufacture: Shanghai Rectron Electronic Co., Ltd.

Make use of the following package products:
SMA(L)/SMB(L)/SMC(L)/SMX/SOD123/SOD123F(L)/MELF/MINI
MELF/R1/A405/DO41/DO15/R3/R6/1.5KE/DO201/DO204/HVM/HVP/DBS/DB/DBLS/SLDBS/MDS/BD
B/RS1/RS2/RS4/RS6/RS8//0RB15/WOM/RC2/BR3/BR6//BR8/BR10/BR15(W)-25(W)-35(W)/MB15(W)-2
5(W)-35(W)/MP15(W)-25(W)-35(W)/RS1M-2M-4M-6M-10M-15M-20M-25M-35M/RBU4M-6M-8M-10M
/(I)TO220A/ITO220/DPK/D2PAK/TO247/SOT23/MDS

Date Received: Nov.25, 2008

Test Period: Nov.25, 2008 – Dec.1, 2008

Test Location: Machinery & Electrical Products Testing Center of Shanghai Entry-Exit
Inspection and Quarantine Bureau of P.R. China
No. 1208, Minsheng Road Pudong Shanghai 200135, P.R.China

Test Requested: Please refer to next pages

Test Method: Please refer to next pages

Test Result: Please refer to next pages

For and on behalf of
SMEC
INSPECTORATE (SHANGHAI) LTD.

Miao Junwen
Director

George Cao
Sr. Supervisor

Report No.: SR081131-2

Test Report

Ref No.: CP2008-1301SH

Date: 12/1/2008

Page: 2 of 4

Test Requested

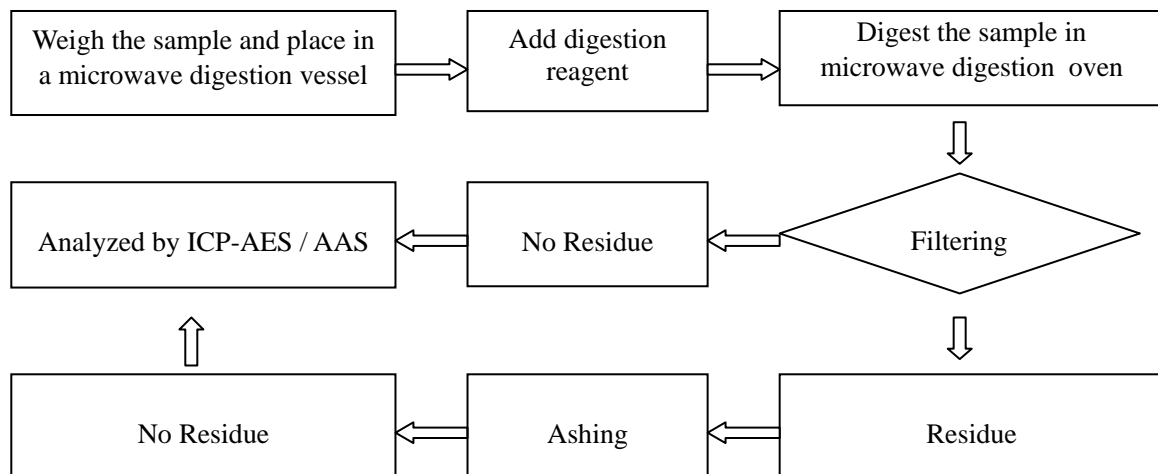
- 1) To determine the Cadmium and Lead content of the submitted sample(s)
- 2) To determine the Mercury content of the submitted sample(s)
- 3) To determine the Hexavalent Chromium content of the submitted sample(s)

Test Method

- 1) With reference to US EPA 3050B/ 3051/ 3052 and other acid digestion methods to determine the content of Cadmium and Lead by ICP-AES or AAS
- 2) With reference to US EPA 3052 to determine the content of Mercury by ICP-AES
- 3) With reference to IEC 62321 Ed.1 2nd, 111/95/CDV. Test for the presence of Hexavalent Chromium by UV-Vis

Test Process

1) Cd and Pb Measurement Flowchart



The samples were dissolved totally by pre-conditioning method according to above flow chart

Report No.: SR081131-2

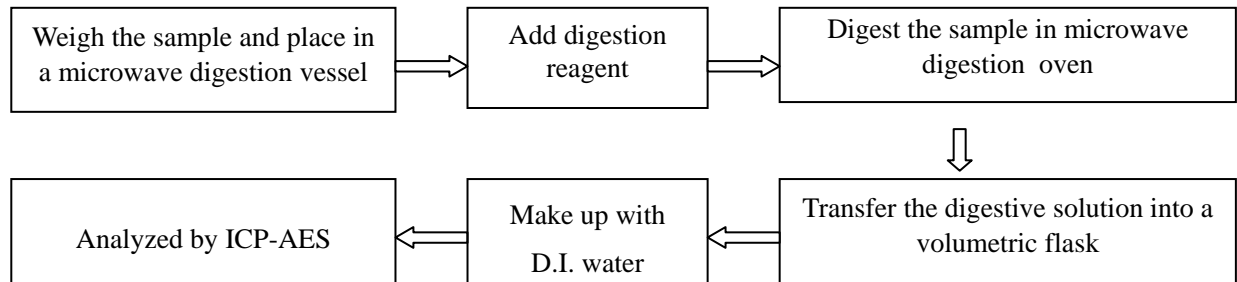
Ref No.: CP2008-1301SH

Date: 12/1/2008

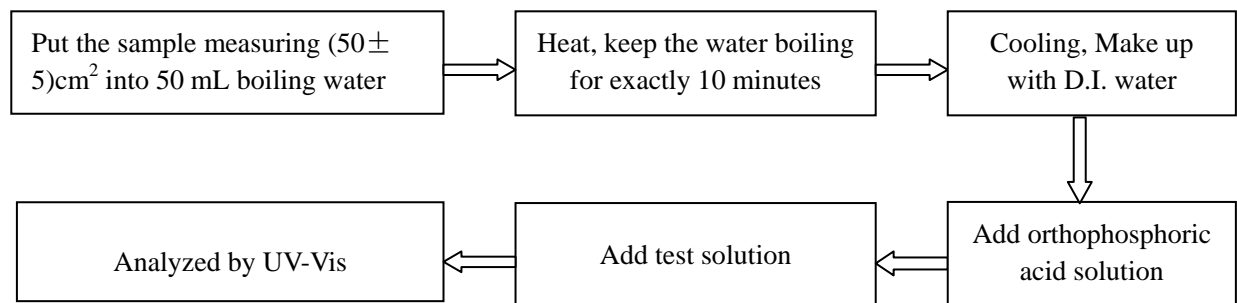
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Test Report

2) Hg Measurement Flowchart



3) Cr⁶⁺ Measurement Flowchart



Test result summary on sample: Solder wafer

Test Item	Unit	Result	Reporting Limit
Cadmium(Cd)	mg/kg	ND	2
Lead (Pb)*	%	92.02	0.002
Mercury (Hg)	mg/kg	ND	2
Hexavalent Chromium (Cr VI)	#	Negative	#

Report No.: SR081131-2

Test Report

Ref No.: CP2008-1301SH

Date: 12/1/2008

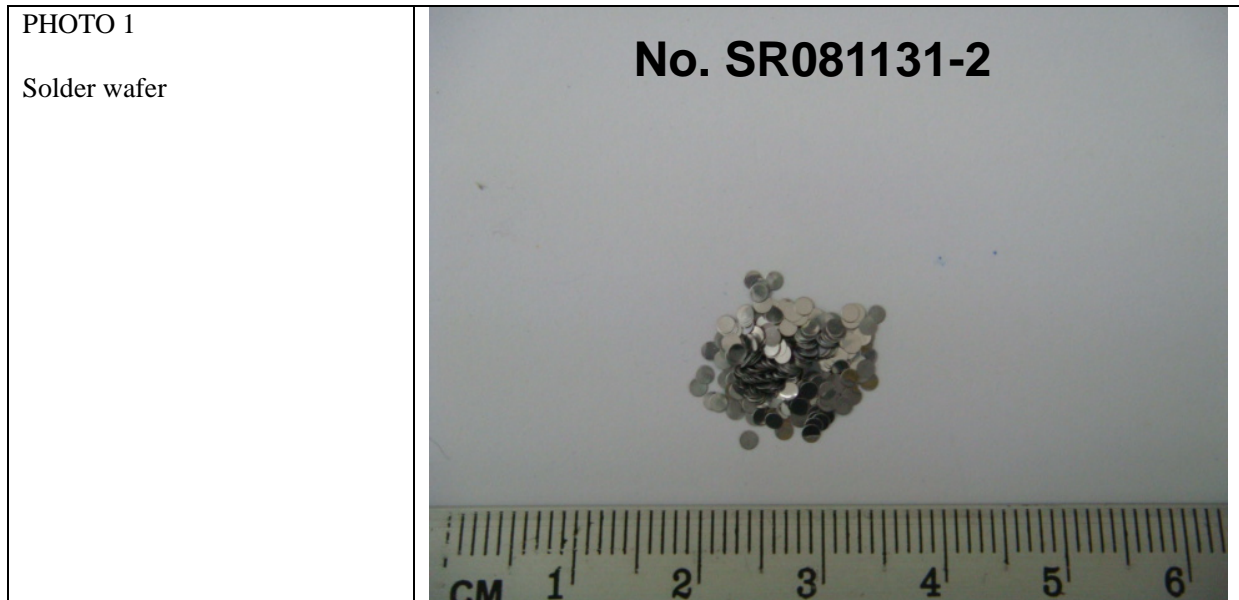
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Note:

- 1) mg/kg = ppm
- 2) ND = Not detected, which will be showed if below reporting limit
- 3) -- = Not applicable
- 4) If residue occurs after digestion, it will be treated by dry ashing for total digestion
- 5) # = Testing Cr VI by IEC 62321 Ed.1 2nd, 111/95/CDV Annex B and the result is showed as Positive/Negative
Negative = Absence of Cr VI, which means that the Cr VI concentration in extraction solution is less than 0.02 mg/kg with 50 cm² sample surface area
Positive = Presence of Cr VI, which means that the Cr VI concentration in extraction solution is equal or greater than 0.02 mg/kg with 50 cm² sample surface area
- 6) *=High concentration sample, and the test result(s) above was/were only for reference.

ANNEX

Sample Photo



*****End of Report*****



上海出入境检验检疫局
机电产品检测技术中心

Machinery & Electrical Products Testing Center of Shanghai CIQ



No. L0232

Report No.: SR081131-3-R1

Ref No.: CP2008-1301SH

Date: 12/9/2008

Page: 1 of 4

Test Report

Applicant: Shanghai Rectron Electronic Co., Ltd.
Address: 188#, New Street, Xia-Sha Town, Nan-Hui Xian, Shanghai, China

Sample Description: The submitted sample(s) stated to be Dice wafer
Model No.: -- Listed No.: --
Lot No.: -- Main Substances: Si
Buyer: SONY
Supplier/Manufacture: Shanghai Rectron Electronic Co., Ltd.

Make use of the following package products:

SMA(L)/SMB(L)/SMC(L)/SMX/SOD123/SOD123F(L)/MELF/MINI
MELF/R1/A405/DO41/DO15/R3/R6/1.5KE/DO201/DO204/HVM/HVP/DBS/DB/DBLS/SLDBS/MDS/BD
B/RS1/RS2/RS4/RS6/RS8//0RB15/WOM/RC2/BR3/BR6//BR8/BR10/BR15(W)-25(W)-35(W)/MB15(W)-2
5(W)-35(W)/MP15(W)-25(W)-35(W)/RS1M-2M-4M-6M-10M-15M-20M-25M-35M/RBU4M-6M-8M-10M
/(I)TO220A/ITO220/DPK/D2PAK/TO247/SOT23/MDS

Date Received: Nov.25, 2008
Test Period: Nov.25, 2008 – Dec.1, 2008
Test Location: Machinery & Electrical Products Testing Center of Shanghai Entry-Exit
Inspection and Quarantine Bureau of P.R. China
No. 1208, Minsheng Road Pudong Shanghai 200135, P.R.China
Test Requested: Please refer to next pages
Test Method: Please refer to next pages
Test Result: Please refer to next pages

For and on behalf of
SMEC
INSPECTORATE (SHANGHAI) LTD.

Miao Junwen
Director

George Cao
Sr. Supervisor

Report No.: SR081131-3-R1

Ref No.: CP2008-1301SH

Date: 12/9/2008

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Test Report

Test Requested

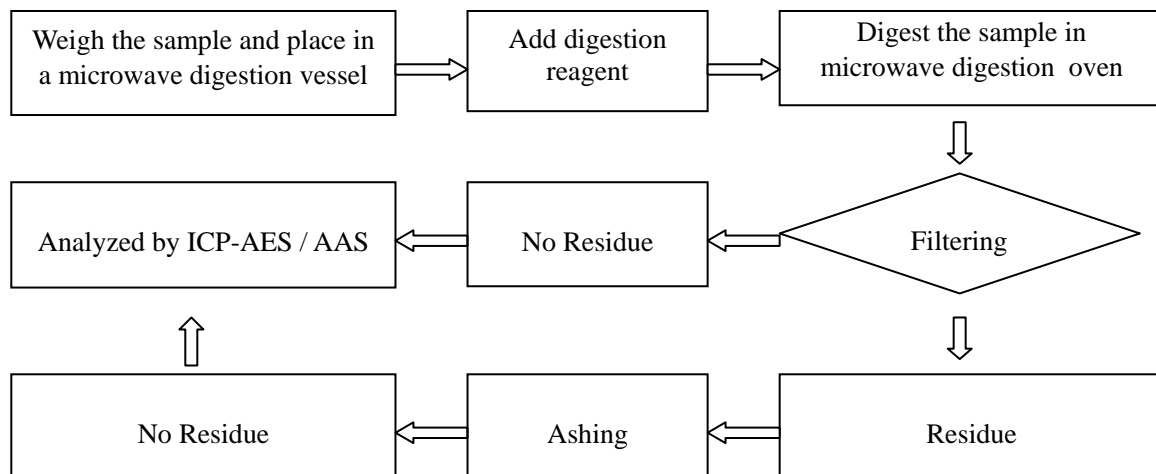
- 1) To determine the Cadmium and Lead content of the submitted sample(s)
- 2) To determine the Mercury content of the submitted sample(s)
- 3) To determine the Hexavalent Chromium content of the submitted sample(s)

Test Method

- 1) With reference to US EPA 3050B/ 3051/ 3052 and other acid digestion methods to determine the content of Cadmium and Lead by ICP-AES or AAS
- 2) With reference to US EPA 3052 to determine the content of Mercury by ICP-AES
- 3) With reference to IEC 62321 Ed.1 2nd, 111/95/CDV. Test for the presence of Hexavalent Chromium by UV-Vis

Test Process

1) Cd and Pb Measurement Flowchart



The samples were dissolved totally by pre-conditioning method according to above flow chart

Report No.: SR081131-3-R1

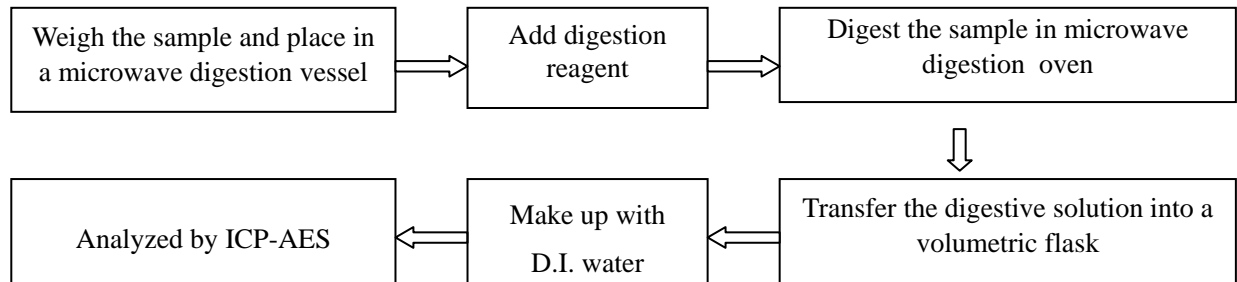
Ref No.: CP2008-1301SH

Date: 12/9/2008

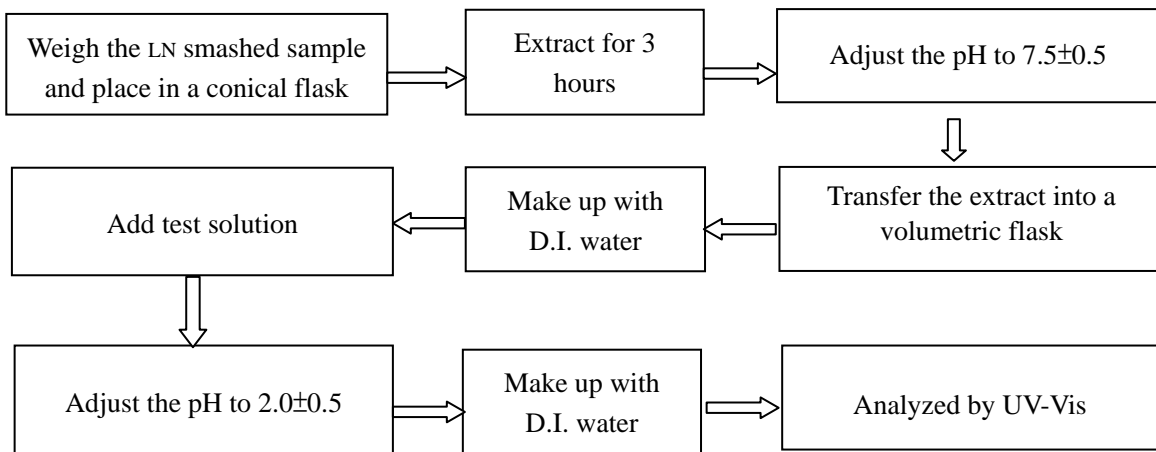
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Test Report

2) Hg Measurement Flowchart



3) Cr⁶⁺ Measurement Flowchart



Test result summary on sample: Dice wafer

Test Item	Unit	Result	Reporting Limit
Cadmium(Cd)	mg/kg	ND	2
Lead (Pb)	mg/kg	ND	2
Mercury (Hg)	mg/kg	ND	2
Hexavalent Chromium (Cr VI)	mg/kg	ND	2

Report No.: SR081131-3-R1

Ref No.: CP2008-1301SH

Date: 12/9/2008

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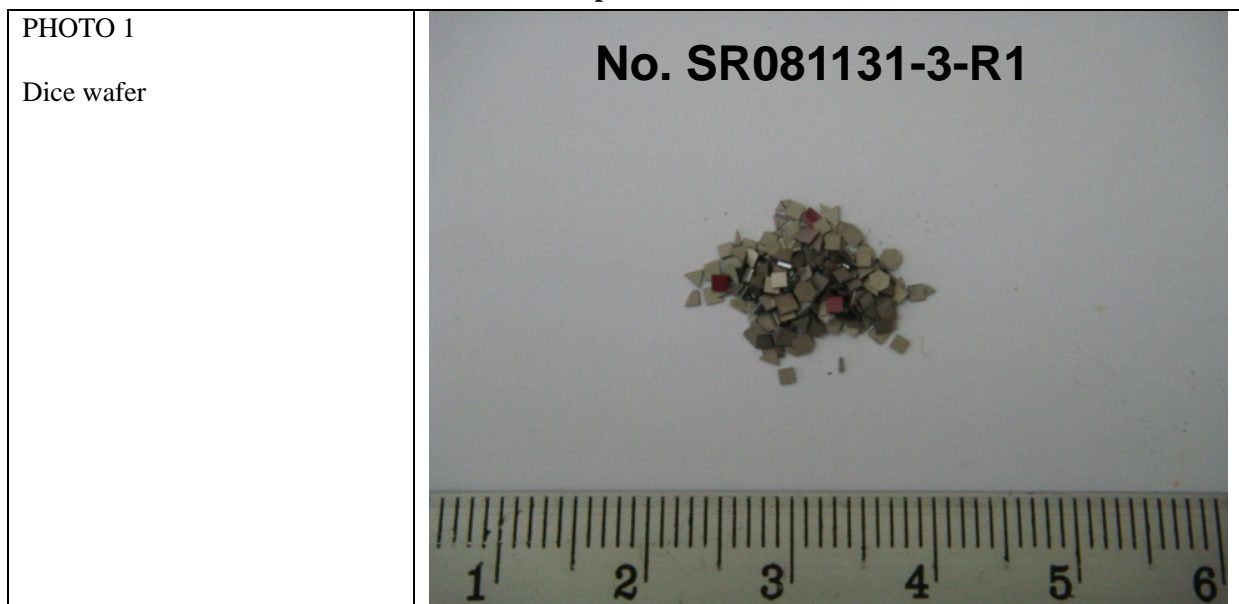
Test Report

Note:

- 1) mg/kg = ppm
- 2) ND = Not detected, which will be showed if below reporting limit
- 3) -- = Not applicable
- 4) If residue occurs after digestion, it will be treated by dry ashing for total digestion
- 5) The report "SR081131-3" was replaced by this report

ANNEX

Sample Photo



*****End of Report*****



上海出入境检验检疫局
机电产品检测技术中心

Machinery & Electrical Products Testing Center of Shanghai CIQ



No. L0232

Report No.: SR081131-4

Ref No.: CP2008-1301SH

Date: 12/1/2008

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Test Report

Applicant: Shanghai Rectron Electronic Co., Ltd.
Address: 188#, New Street, Xia-Sha Town, Nan-Hui Xian, Shanghai, China

Sample Description: The submitted sample(s) stated to be Lead wire

Model No.: -- Listed No.: --

Lot No.: -- Main Substances: Cu

Buyer: SONY

Supplier/Manufacture: Shanghai Rectron Electronic Co., Ltd.

Make use of the following package products:
SMA(L)/SMB(L)/SMC(L)/SMX/SOD123/SOD123F(L)/MELF/MINI
MELF/R1/A405/DO41/DO15/R3/R6/1.5KE/DO201/DO204/HVM/HVP/DBS/DB/DBLS/SLDBS/MDS/BD
B/RS1/RS2/RS4/RS6/RS8//0RB15/WOM/RC2/BR3/BR6//BR8/BR10/BR15(W)-25(W)-35(W)/MB15(W)-2
5(W)-35(W)/MP15(W)-25(W)-35(W)/RS1M-2M-4M-6M-10M-15M-20M-25M-35M/RBU4M-6M-8M-10M
/(I)TO220A/ITO220/DPK/D2PAK/TO247/SOT23/MDS

Date Received: Nov.25, 2008

Test Period: Nov.25, 2008 – Dec.1, 2008

Test Location: Machinery & Electrical Products Testing Center of Shanghai Entry-Exit
Inspection and Quarantine Bureau of P.R. China
No. 1208, Minsheng Road Pudong Shanghai 200135, P.R.China

Test Requested: Please refer to next pages

Test Method: Please refer to next pages

Test Result: Please refer to next pages

For and on behalf of
SMEC
INSPECTORATE (SHANGHAI) LTD.

Miao Junwen
Director

George Cao
Sr. Supervisor

Report No.: SR081131-4

Test Report

Ref No.: CP2008-1301SH

Date: 12/1/2008

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Test Requested

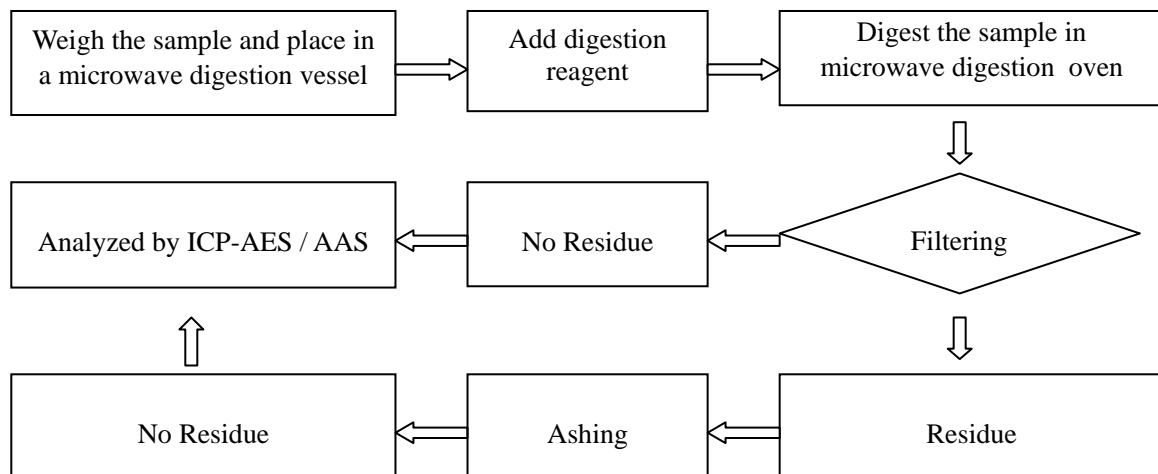
- 1) To determine the Cadmium and Lead content of the submitted sample(s)
- 2) To determine the Mercury content of the submitted sample(s)
- 3) To determine the Hexavalent Chromium content of the submitted sample(s)

Test Method

- 1) With reference to US EPA 3050B/ 3051/ 3052 and other acid digestion methods to determine the content of Cadmium and Lead by ICP-AES or AAS
- 2) With reference to US EPA 3052 to determine the content of Mercury by ICP-AES
- 3) With reference to IEC 62321 Ed.1 2nd, 111/95/CDV. Test for the presence of Hexavalent Chromium by UV-Vis

Test Process

1) Cd and Pb Measurement Flowchart



The samples were dissolved totally by pre-conditioning method according to above flow chart

Report No.: SR081131-4

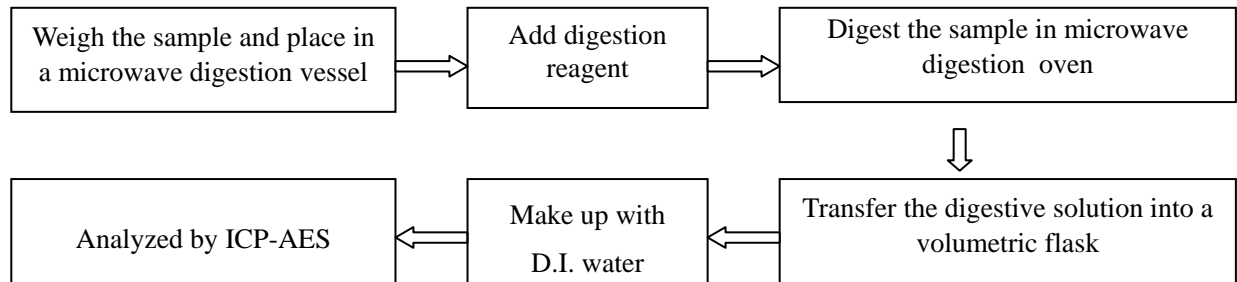
Ref No.: CP2008-1301SH

Date: 12/1/2008

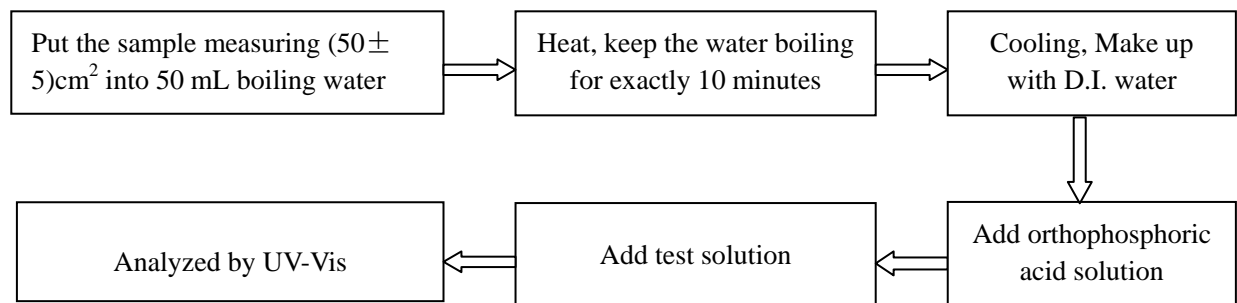
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Test Report

2) Hg Measurement Flowchart



3) Cr⁶⁺ Measurement Flowchart



Test result summary on sample: Lead wire

Test Item	Unit	Result	Reporting Limit
Cadmium(Cd)	mg/kg	ND	2
Lead (Pb)	mg/kg	ND	2
Mercury (Hg)	mg/kg	ND	2
Hexavalent Chromium (Cr VI)	#	Negative	#

Report No.: SR081131-4

Test Report

Ref No.: CP2008-1301SH

Date: 12/1/2008

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Note:

- 1) mg/kg = ppm
- 2) ND = Not detected, which will be showed if below reporting limit
- 3) -- = Not applicable
- 4) If residue occurs after digestion, it will be treated by dry ashing for total digestion
- 5) # = Testing Cr VI by IEC 62321 Ed.1 2nd, 111/95/CDV Annex B and the result is showed as Positive/Negative
Negative = Absence of Cr VI, which means that the Cr VI concentration in extraction solution is less than 0.02 mg/kg with 50 cm² sample surface area
Positive = Presence of Cr VI, which means that the Cr VI concentration in extraction solution is equal or greater than 0.02 mg/kg with 50 cm² sample surface area

ANNEX

Sample Photo



*****End of Report*****



Report No.: SR081131-5

Ref No.: CP2008-1301SH

Date: 12/11/2008

Page: 1 of 6

Test Report

Applicant: Shanghai Rectron Electronic Co., Ltd.
Address: 188#, New Street, Xia-Sha Town, Nan-Hui Xian, Shanghai, China

Sample Description: The submitted sample(s) stated to be Silicon rubber
Model No.: -- Listed No.: --
Lot No.: -- Main Substances: Si
Buyer: SONY
Supplier/Manufacture: Shanghai Rectron Electronic Co., Ltd.

Make use of the following package products:

SMA(L)/SMB(L)/SMC(L)/SMX/SOD123/SOD123F(L)/MELF/MINI
MELF/R1/A405/DO41/DO15/R3/R6/1.5KE/DO201/DO204/HVM/HVP/DBS/DB/DBLS/SLDBS/MDS/BD
B/RS1/RS2/RS4/RS6/RS8//0RB15/WOM/RC2/BR3/BR6//BR8/BR10/BR15(W)-25(W)-35(W)/MB15(W)-2
5(W)-35(W)/MP15(W)-25(W)-35(W)/RS1M-2M-4M-6M-10M-15M-20M-25M-35M/RBU4M-6M-8M-10M
/(I)TO220A/ITO220/DPK/D2PAK/TO247/SOT23/MDS

Date Received: Nov.25, 2008
Test Period: Nov.25, 2008 – Dec.11, 2008
Test Location: Machinery & Electrical Products Testing Center of Shanghai Entry-Exit
Inspection and Quarantine Bureau of P.R. China
No. 1208, Minsheng Road Pudong Shanghai 200135, P.R.China
Test Requested: Please refer to next pages
Test Method: Please refer to next pages
Test Result: Please refer to next pages

For and on behalf of
SMEC
INSPECTORATE (SHANGHAI) LTD.

Miao Junwen
Director

George Cao
Sr. Supervisor

Report No.: SR081131-5

Test Report

Ref No.: CP2008-1301SH

Date: 12/11/2008

Page: 2 of 6

Test Requested

- 1) To determine the Cadmium and Lead content of the submitted sample(s)
- 2) To determine the Mercury content of the submitted sample(s)
- 3) To determine the Hexavalent Chromium content of the submitted sample(s)
- 4) To determine the PBBs and PBDEs contents of the submitted sample(s)
- 5) To determine the PFOS&PFOA contents of the submitted sample(s)
- 6) To determine the TBBP-A contents of the submitted sample(s)
- 7) To determine the Phthalates DBP, BBP, DEHP, DINP, DNOP, DIDP and DNHP contents of the submitted sample(s)

Test Method

- 1) With reference to US EPA 3050B/ 3051/ 3052 and other acid digestion methods to determine the content of Cadmium and Lead by ICP-AES or AAS
- 2) With reference to US EPA 3052 to determine the content of Mercury by ICP-AES
- 3) With reference to US EPA 3060A/ 7196A to determine the content of Hexavalent Chromium by UV-Vis
- 4) With reference to US EPA 8081A/ 8270D/ 3540C/ 3550C to determine the contents of PBBs and PBDEs by GC/MS
- 5) With reference to US EPA 3540C/3550C method. Analysis was performed by LC-MS.
- 6) With reference to US EPA3540C/8270D. Determination of TBBP-A by GC/MS
- 7) With reference to ASTM D3421-75. Analysis was performed by GC-MS

Report No.: SR081131-5

Ref No.: CP2008-1301SH

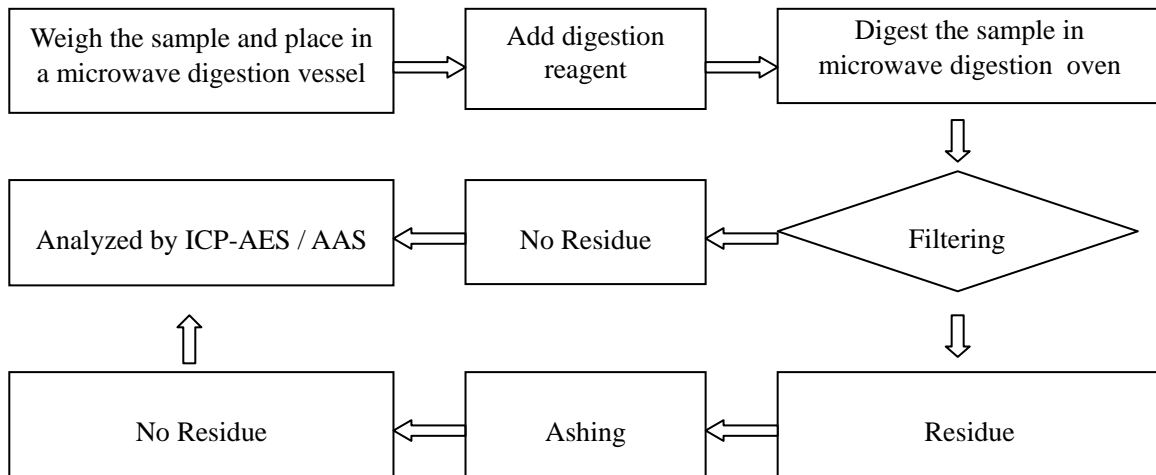
Date: 12/11/2008

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Test Report

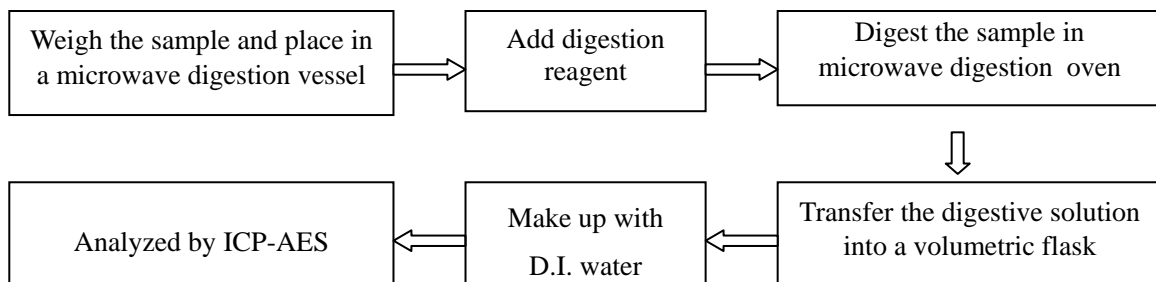
Test Process

1) Cd and Pb Measurement Flowchart

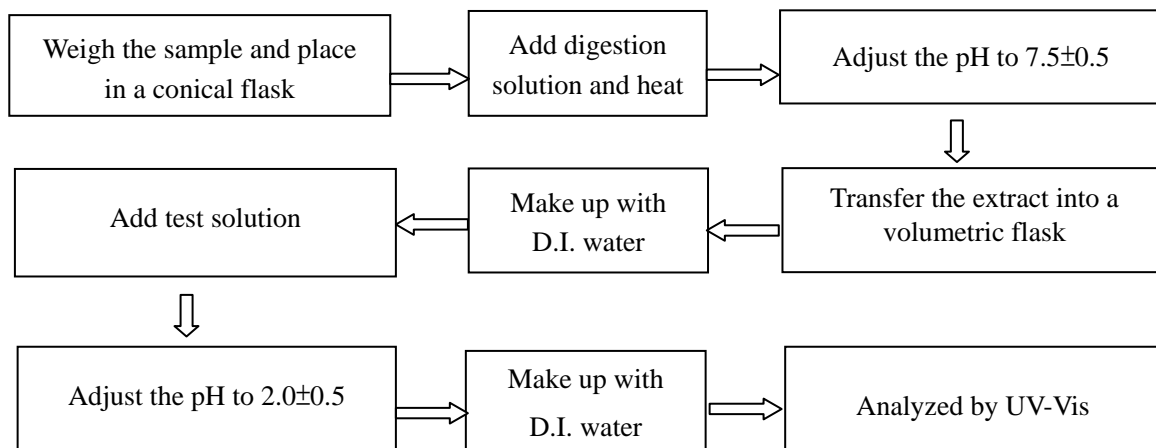


The samples were dissolved totally by pre-conditioning method according to above flow chart

2) Hg Measurement Flowchart



3) Cr⁶⁺ Measurement Flowchart



Report No.: SR081131-5

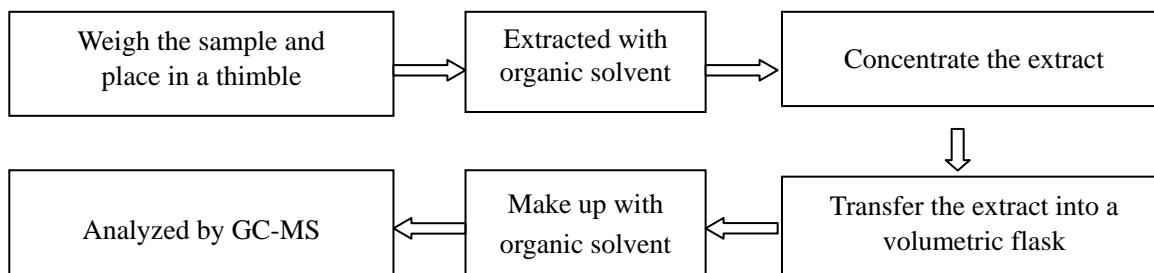
Ref No.: CP2008-1301SH

Date: 12/11/2008

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Test Report

4) PBBs /PBDEs Measurement Flowchart



Test result summary on sample: Silicon rubber

Test Item	Unit	Result	Reporting Limit
Cadmium(Cd)	mg/kg	ND	2
Lead (Pb)	mg/kg	ND	2
Mercury (Hg)	mg/kg	ND	2
Hexavalent Chromium (CrVI)	mg/kg	ND	2
Polybrominated Biphenyls (PBBs)			
1. Monobromobiphenyls	mg/kg	ND	5
2. Dibromobiphenyls	mg/kg	ND	5
3. Tribromobiphenyls	mg/kg	ND	5
4. Tetrabromobiphenyls	mg/kg	ND	5
5. Pentabromobiphenyls	mg/kg	ND	5
6. Hexabromobiphenyls	mg/kg	ND	5
7. Heptabromobiphenyls	mg/kg	ND	5
8. Octabromobiphenyls	mg/kg	ND	5
9. Nonabromobiphenyls	mg/kg	ND	5
10. Decabromobiphenyls	mg/kg	ND	5
Sum of PBBs	mg/kg	ND	--
Polybrominated Diphenyl Ethers (PBDEs)			
1. Monobromodiphenyl ethers	mg/kg	ND	5
2. Dibromodiphenyl ethers	mg/kg	ND	5
3. Tribromodiphenyl ethers	mg/kg	ND	5
4. Tetrabromodiphenyl ethers	mg/kg	ND	5
5. Pentabromodiphenyl ethers	mg/kg	ND	5
6. Hexabromodiphenyl ethers	mg/kg	ND	5
7. Heptabromodiphenyl ethers	mg/kg	ND	5
8. Octabromodiphenyl ethers	mg/kg	ND	5
9. Nonabromodiphenyl ethers	mg/kg	ND	5
10. Decabromodiphenyl ethers	mg/kg	ND	5
Sum of PBDE	mg/kg	ND	--

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Ref No.: CP2008-1301SH

Date: 12/11/2008

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Test Report

Test Item	Unit	Result	Reporting Limit
PFOS			
PFOS	mg/kg	ND	10
PFOA			
PFOA	mg/kg	ND	10
TBBP-A			
TBBP-A	mg/kg	ND	5
Phthalates			
Di-butyl phthalate(DBP)	%	ND	0.003
Benzyl butyl phthalate(BBP)	%	ND	0.003
Di-2-ethylhexyl phthalate(DEHP)	%	ND	0.003
Di-isononyl phthalate(DINP)	%	ND	0.01
Di-n-octyl phthalate(DNOP)	%	ND	0.003
Di-isodecyl phthalate(DIDP)	%	ND	0.01
Di-n-hexyl phthalate(DNHP)	%	ND	0.003

Note:

- 1) mg/kg = ppm
- 2) ND = Not detected, which will be showed if below reporting limit
- 3) -- = Not applicable
- 4) If residue occurs after digestion, it will be treated by dry ashing for total digestion
- 5) Reference information: EU Directive 2006/122/EC
 - i) May not be placed on the market or used as a substance or constituent of preparations in a concentration equal to or higher than 0.005 % by mass.
 - ii) May not be placed on the market in semi-finished products or articles, or parts thereof, if the concentration of PFOS is equal to or higher than 0.1 % by mass calculated with reference to the mass of structurally or microstructurally distinct parts that contain PFOS or, for textiles or other coated materials, if the amount of PFOS is equal to or higher than $1 \mu \text{g/m}^2$ of the coated material.

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Ref No.: CP2008-1301SH

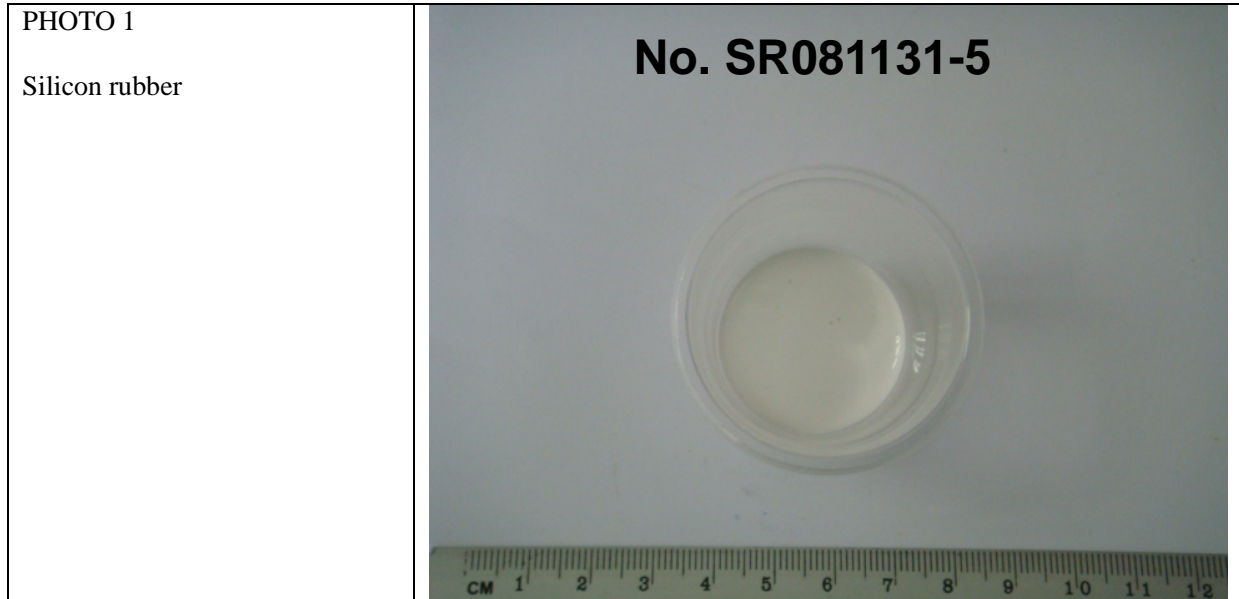
Date: 12/11/2008

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Test Report

ANNEX

Sample Photo



*****End of Report*****



上海出入境检验检疫局
机电产品检测技术中心

Machinery & Electrical Products Testing Center of Shanghai CIQ



No. L0232

Report No.: SR081131-6

Ref No.: CP2008-1301SH

Date: 12/1/2008

Page: 1 of 4

Test Report

Applicant: Shanghai Rectron Electronic Co., Ltd.
Address: 188#, New Street, Xia-Sha Town, Nan-Hui Xian, Shanghai, China

Sample Description: The submitted sample(s) stated to be UV Ink
Model No.: -- Listed No.: --
Lot No.: -- Main Substances: Ink
Buyer: SONY
Supplier/Manufacture: Shanghai Rectron Electronic Co., Ltd.

Make use of the following package products:

SMA(L)/SMB(L)/SMC(L)/SMX/SOD123/SOD123F(L)/MELF/MINI
MELF/R1/A405/DO41/DO15/R3/R6/1.5KE/DO201/DO204/HVM/HVP/DBS/DB/DBLS/SLDBS/MDS/BD
B/RS1/RS2/RS4/RS6/RS8//0RB15/WOM/RC2/BR3/BR6//BR8/BR10/BR15(W)-25(W)-35(W)/MB15(W)-2
5(W)-35(W)/MP15(W)-25(W)-35(W)/RS1M-2M-4M-6M-10M-15M-20M-25M-35M/RBU4M-6M-8M-10M
/(I)TO220A/ITO220/DPK/D2PAK/TO247/SOT23/MDS

Date Received: Nov.25, 2008
Test Period: Nov.25, 2008 – Dec.1, 2008
Test Location: Machinery & Electrical Products Testing Center of Shanghai Entry-Exit
Inspection and Quarantine Bureau of P.R. China
No. 1208, Minsheng Road Pudong Shanghai 200135, P.R.China
Test Requested: Please refer to next pages
Test Method: Please refer to next pages
Test Result: Please refer to next pages

For and on behalf of
SMEC
INSPECTORATE (SHANGHAI) LTD.

Miao Junwen
Director

George Cao
Sr. Supervisor

Report No.: SR081131-6

Test Report

Ref No.: CP2008-1301SH

Date: 12/1/2008

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Test Requested

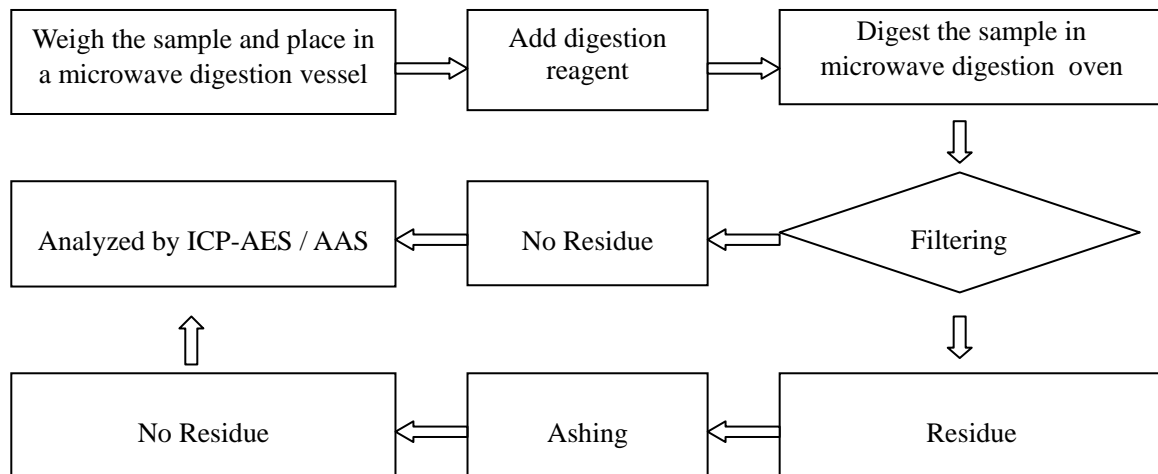
- 1) To determine the Cadmium and Lead content of the submitted sample(s)
- 2) To determine the Mercury content of the submitted sample(s)
- 3) To determine the Hexavalent Chromium content of the submitted sample(s)

Test Method

- 1) With reference to US EPA 3050B/ 3051/ 3052 and other acid digestion methods to determine the content of Cadmium and Lead by ICP-AES or AAS
- 2) With reference to US EPA 3052 to determine the content of Mercury by ICP-AES
- 3) With reference to US EPA 3060A/ 7196A to determine the content of Hexavalent Chromium by UV-Vis

Test Process

1) Cd and Pb Measurement Flowchart



The samples were dissolved totally by pre-conditioning method according to above flow chart

Report No.: SR081131-6

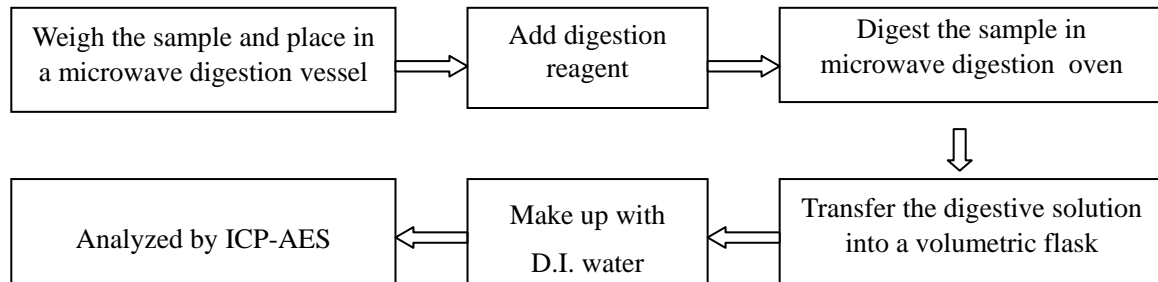
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Date: 12/1/2008

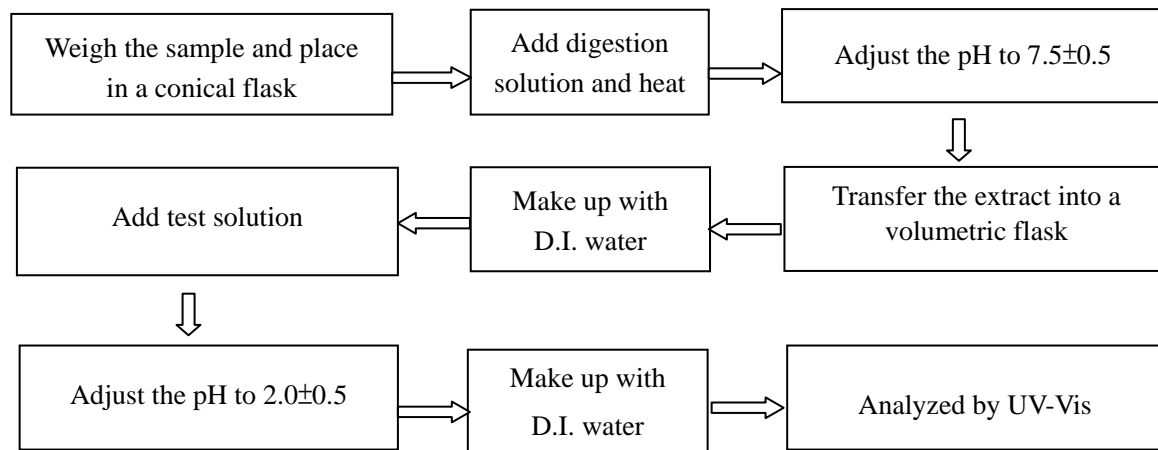
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Test Report

2) Hg Measurement Flowchart



3) Cr⁶⁺ Measurement Flowchart



Test result summary on sample: UV Ink

Test Item	Unit	Result	Reporting Limit
Cadmium(Cd)	mg/kg	ND	2
Lead (Pb)	mg/kg	ND	2
Mercury (Hg)	mg/kg	ND	2
Hexavalent Chromium (CrVI)	mg/kg	ND	2

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Ref No.: CP2008-1301SH

Date: 12/1/2008

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Test Report

Note:

- 1) mg/kg = ppm
- 2) ND = Not detected, which will be showed if below reporting limit
- 3) -- = Not applicable
- 4) If residue occurs after digestion, it will be treated by dry ashing for total digestion

ANNEX

Sample Photo



*****End of Report*****



上海出入境检验检疫局
机电产品检测技术中心

Machinery & Electrical Products Testing Center of Shanghai CIQ



No. L0232

Report No.: SR081131-7

Ref No.: CP2008-1301SH

Date: 12/1/2008

Page: 1 of 4

Test Report

Applicant: Shanghai Rectron Electronic Co., Ltd.
Address: 188#, New Street, Xia-Sha Town, Nan-Hui Xian, Shanghai, China

Sample Description: The submitted sample(s) stated to be Plating
Model No.: -- Listed No.: --
Lot No.: -- Main Substances: Sn
Buyer: SONY
Supplier/Manufacture: Shanghai Rectron Electronic Co., Ltd.

Make use of the following package products:

SMA(L)/SMB(L)/SMC(L)/SMX/SOD123/SOD123F(L)/MELF/MINI
MELF/R1/A405/DO41/DO15/R3/R6/1.5KE/DO201/DO204/HVM/HVP/DBS/DB/DBLS/SLDBS/MDS/BD
B/RS1/RS2/RS4/RS6/RS8//0RB15/WOM/RC2/BR3/BR6//BR8/BR10/BR15(W)-25(W)-35(W)/MB15(W)-2
5(W)-35(W)/MP15(W)-25(W)-35(W)/RS1M-2M-4M-6M-10M-15M-20M-25M-35M/RBU4M-6M-8M-10M
/(I)TO220A/ITO220/DPK/D2PAK/TO247/SOT23/MDS

Date Received: Nov.25, 2008
Test Period: Nov.25, 2008 – Dec.1, 2008
Test Location: Machinery & Electrical Products Testing Center of Shanghai Entry-Exit
Inspection and Quarantine Bureau of P.R. China
No. 1208, Minsheng Road Pudong Shanghai 200135, P.R.China
Test Requested: Please refer to next pages
Test Method: Please refer to next pages
Test Result: Please refer to next pages

For and on behalf of
SMEC
INSPECTORATE (SHANGHAI) LTD.

Miao Junwen
Director

George Cao
Sr. Supervisor

Report No.: SR081131-7

Test Report

Ref No.: CP2008-1301SH

Date: 12/1/2008

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Test Requested

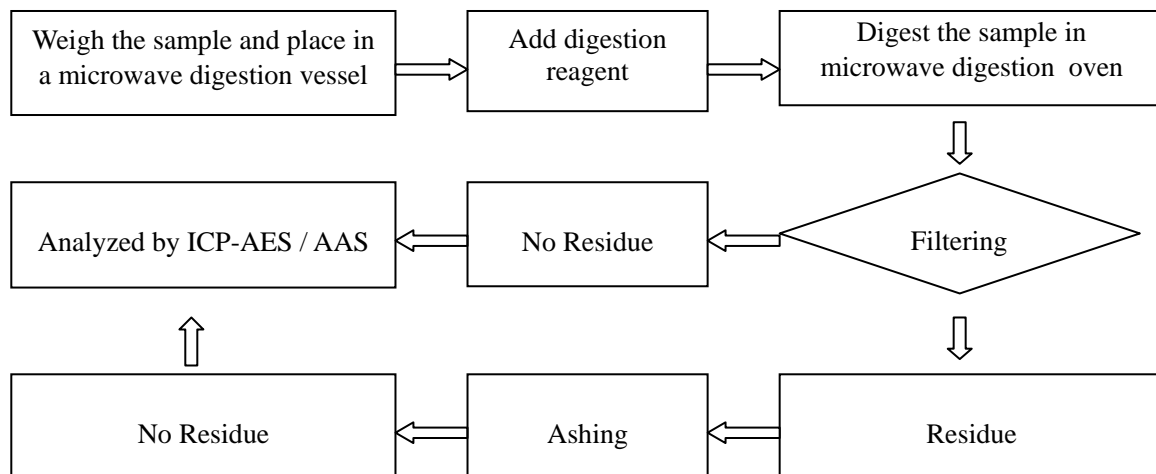
- 1) To determine the Cadmium and Lead content of the submitted sample(s)
- 2) To determine the Mercury content of the submitted sample(s)
- 3) To determine the Hexavalent Chromium content of the submitted sample(s)

Test Method

- 1) With reference to US EPA 3050B/ 3051/ 3052 and other acid digestion methods to determine the content of Cadmium and Lead by ICP-AES or AAS
- 2) With reference to US EPA 3052 to determine the content of Mercury by ICP-AES
- 3) With reference to IEC 62321 Ed.1 2nd, 111/95/CDV. Test for the presence of Hexavalent Chromium by UV-Vis

Test Process

1) Cd and Pb Measurement Flowchart



The samples were dissolved totally by pre-conditioning method according to above flow chart

Report No.: SR081131-7

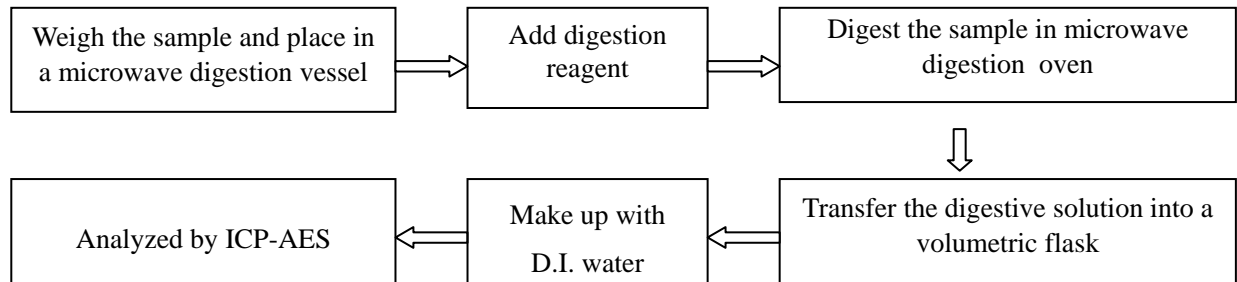
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Date: 12/1/2008

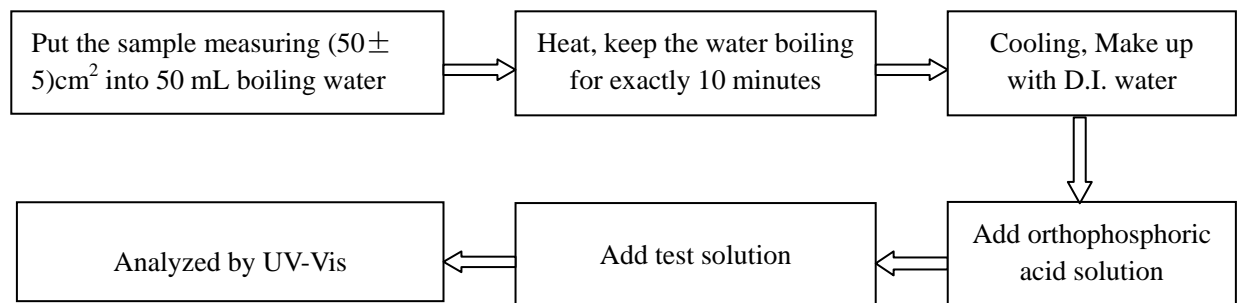
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Test Report

2) Hg Measurement Flowchart



3) Cr⁶⁺ Measurement Flowchart



Test result summary on sample: Plating

Test Item	Unit	Result	Reporting Limit
Cadmium(Cd)	mg/kg	ND	2
Lead (Pb)	mg/kg	73	2
Mercury (Hg)	mg/kg	ND	2
Hexavalent Chromium (Cr VI)	#	Negative	#

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Test Report

Ref No.: CP2008-1301SH

Date: 12/1/2008

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Note:

- 1) mg/kg = ppm
- 2) ND = Not detected, which will be showed if below reporting limit
- 3) -- = Not applicable
- 4) If residue occurs after digestion, it will be treated by dry ashing for total digestion
- 5) # = Testing Cr VI by IEC 62321 Ed.1 2nd, 111/95/CDV Annex B and the result is showed as Positive/Negative
Negative = Absence of Cr VI, which means that the Cr VI concentration in extraction solution is less than 0.02 mg/kg with 50 cm² sample surface area
Positive = Presence of Cr VI, which means that the Cr VI concentration in extraction solution is equal or greater than 0.02 mg/kg with 50 cm² sample surface area

ANNEX

Sample Photo



*****End of Report*****